

## Features

- Low-Voltage and Standard-Voltage Operation
  - 2.7 ( $V_{CC} = 2.7V$  to 5.5V)
  - 2.5 ( $V_{CC} = 2.5V$  to 5.5V)
- 3-Wire Serial Interface
- Schmitt Trigger, Filtered Inputs for Noise Suppression
- 2 MHz Clock Rate (5V)
- Self-Timed Write Cycle (10 ms max)
- High Reliability
  - Endurance: 1 Million Write Cycles
  - Data Retention: 100 Years
- Automotive Grade and Extended Temperature Devices Available
- 8-lead PDIP and 8-lead JEDEC SOIC Packages

## Description

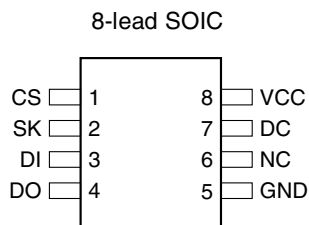
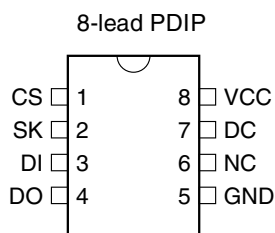
The AT93C46C provides 1024 bits of serial electrically-erasable programmable read only memory (EEPROM) organized as 64 words of 16 bits each. The device is optimized for use in many industrial and commercial applications where low-power and low-voltage operation are essential. The AT93C46C is available in space saving 8-lead PDIP and 8-lead JEDEC SOIC packages.

The AT93C46C is enabled through the Chip Select pin (CS), and accessed via a 3-wire serial interface consisting of Data Input (DI), Data Output (DO), and Shift Clock (SK). Upon receiving a READ instruction at DI, the address is decoded and the data is clocked out serially on the data output pin DO. The WRITE cycle is completely self-timed and no separate ERASE cycle is required before WRITE. The WRITE cycle is only enabled when the part is in the ERASE/WRITE ENABLE state. When CS is brought “high” following the initiation of a WRITE cycle, the DO pin outputs the READY/BUSY status of the part.

The AT93C46C is available in 2.7V to 5.5V and 2.5V to 5.5V versions.

## Pin Configurations

| Pin Name | Function           |
|----------|--------------------|
| CS       | Chip Select        |
| SK       | Serial Data Clock  |
| DI       | Serial Data Input  |
| DO       | Serial Data Output |
| GND      | Ground             |
| VCC      | Power Supply       |
| NC       | No Connect         |
| DC       | Don't Connect      |



## 3-Wire Serial EEPROM

1K (64 x 16)

## AT93C46C

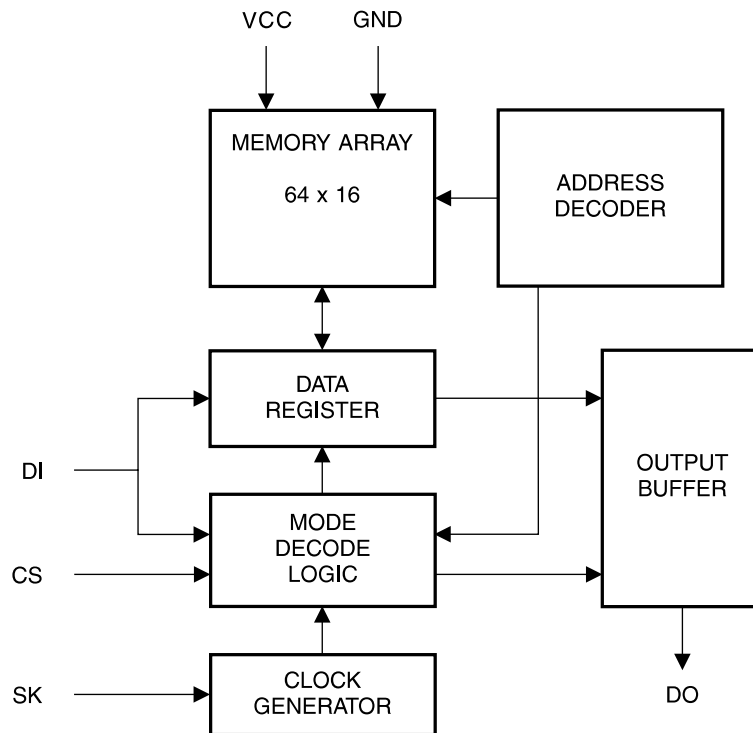


## Absolute Maximum Ratings\*

|  |                 |
|--|-----------------|
| Operating Temperature .....                        | -55°C to +125°C |
| Storage Temperature .....                          | -65°C to +150°C |
| Voltage on Any Pin<br>with Respect to Ground ..... | -1.0V to +7.0V  |
| Maximum Operating Voltage .....                    | 6.25V           |
| DC Output Current.....                             | 5.0 mA          |

\*NOTICE: Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

## Block Diagram



## Pin Capacitance<sup>(1)</sup>

Applicable over recommended operating range from  $T_A = 25^\circ\text{C}$ ,  $f = 1.0\text{ MHz}$ ,  $V_{CC} = +5.0\text{V}$  (unless otherwise noted).

| Symbol    | Test Conditions                | Max | Units | Conditions            |
|-----------|--------------------------------|-----|-------|-----------------------|
| $C_{OUT}$ | Output Capacitance (DO)        | 5   | pF    | $V_{OUT} = 0\text{V}$ |
| $C_{IN}$  | Input Capacitance (CS, SK, DI) | 5   | pF    | $V_{IN} = 0\text{V}$  |

Note: 1. This parameter is characterized and is not 100% tested.

## DC Characteristics

Applicable over recommended operating range from:  $T_{AI} = -40^\circ\text{C}$  to  $+85^\circ\text{C}$ ,  $V_{CC} = +2.5\text{V}$  to  $+5.5\text{V}$ ,  
 $T_{AC} = 0^\circ\text{C}$  to  $+70^\circ\text{C}$ ,  $V_{CC} = +2.5\text{V}$  to  $+5.5\text{V}$  (unless otherwise noted).

| Symbol                             | Parameter                                 | Test Condition                             | Min                          | Typ                         | Max                                 | Units         |
|------------------------------------|---|--|------------------------------|-----------------------------|-------------------------------------|---------------|
| $V_{CC1}$                          | Supply Voltage                            |  | 2.5                          |                             | 5.5                                 | V             |
| $V_{CC2}$                          | Supply Voltage                            |  | 2.7                          |                             | 5.5                                 | V             |
| $V_{CC3}$                          | Supply Voltage                            |  | 4.5                          |                             | 5.5                                 | V             |
| $I_{CC}$                           | Supply Current                            | $V_{CC} = 5.0\text{V}$                     | READ at 1.0 MHz              | 0.5                         | 2.0                                 | mA            |
|                                    |   |  | WRITE at 1.0 MHz             | 0.5                         | 2.0                                 | mA            |
| $I_{SB1}$                          | Standby Current                           | $V_{CC} = 2.5\text{V}$                     | CS = 0V                      | 14.0                        | 20.0                                | $\mu\text{A}$ |
| $I_{SB2}$                          | Standby Current                           | $V_{CC} = 2.7\text{V}$                     | CS = 0V                      | 14.0                        | 20.0                                | $\mu\text{A}$ |
| $I_{SB3}$                          | Standby Current                           | $V_{CC} = 5.0\text{V}$                     | CS = 0V                      | 35.0                        | 50.0                                | $\mu\text{A}$ |
| $I_{IL}$                           | Input Leakage                             | $V_{IN} = 0\text{V}$ to $V_{CC}$           |                              | 0.1                         | 1.0                                 | $\mu\text{A}$ |
| $I_{OL}$                           | Output Leakage                            | $V_{IN} = 0\text{V}$ to $V_{CC}$           |                              | 0.1                         | 1.0                                 | $\mu\text{A}$ |
| $V_{IL1}^{(1)}$<br>$V_{IH1}^{(1)}$ | Input Low Voltage<br>Input High Voltage   | $2.5\text{V} \leq V_{CC} \leq 5.5\text{V}$ |                              | -0.6<br>$V_{CC} \times 0.7$ | $V_{CC} \times 0.3$<br>$V_{CC} + 1$ | V             |
| $V_{OL1}$<br>$V_{OH1}$             | Output Low Voltage<br>Output High Voltage | $4.5\text{V} \leq V_{CC} \leq 5.5\text{V}$ | $I_{OL} = 2.1\text{ mA}$     |                             | 0.4                                 | V             |
|                                    |   |  | $I_{OH} = -0.4\text{ mA}$    | 2.4                         |                                     | V             |
| $V_{OL2}$<br>$V_{OH2}$             | Output Low Voltage<br>Output High Voltage | $2.5\text{V} \leq V_{CC} \leq 2.7\text{V}$ | $I_{OL} = 0.15\text{ mA}$    |                             | 0.2                                 | V             |
|                                    |   |  | $I_{OH} = -100\ \mu\text{A}$ | $V_{CC} - 0.2$              |                                     | V             |

Note: 1.  $V_{IL}$  min and  $V_{IH}$  max are reference only and are not tested.

## AC Characteristics

Applicable over recommended operating range from  $T_A = -40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$ ,  $V_{CC} = +2.5\text{V}$  to  $+5.5\text{V}$ ,  
 $CL = 1$  TTL Gate and  $100\text{ pF}$  (unless otherwise noted).

| Symbol                   | Parameter                  | Test Condition   | Min               | Typ | Max               | Units       |
|--------------------------|----------------------------|--|-------------------|-----|-------------------|-------------|
| $f_{SK}$                 | SK Clock Frequency         | $4.5\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.7\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.5\text{V} \leq V_{CC} \leq 5.5\text{V}$                             | 0<br>0<br>0       |     | 2<br>1<br>0.5     | MHz         |
| $t_{SKH}$                | SK High Time               | $4.5\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.7\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.5\text{V} \leq V_{CC} \leq 5.5\text{V}$                             | 250<br>250<br>500 |     |                   | ns          |
| $t_{SKL}$                | SK Low Time                | $4.5\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.7\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.5\text{V} \leq V_{CC} \leq 5.5\text{V}$                             | 250<br>250<br>500 |     |                   | ns          |
| $t_{CS}$                 | Minimum CS Low Time        | $4.5\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.7\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.5\text{V} \leq V_{CC} \leq 5.5\text{V}$                             | 250<br>250<br>500 |     |                   | ns          |
| $t_{CSS}$                | CS Setup Time              | Relative to SK<br>$4.5\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.7\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.5\text{V} \leq V_{CC} \leq 5.5\text{V}$           | 50<br>50<br>100   |     |                   | ns          |
| $t_{DIS}$                | DI Setup Time              | Relative to SK<br>$4.5\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.7\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.5\text{V} \leq V_{CC} \leq 5.5\text{V}$           | 100<br>100<br>200 |     |                   | ns          |
| $t_{CSH}$                | CS Hold Time               | Relative to SK   | 0                 |     |                   | ns          |
| $t_{DIH}$                | DI Hold Time               | Relative to SK<br>$4.5\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.7\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.5\text{V} \leq V_{CC} \leq 5.5\text{V}$           | 100<br>100<br>200 |     |                   | ns          |
| $t_{PD1}$                | Output Delay to '1'        | AC Test<br>$4.5\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.7\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.5\text{V} \leq V_{CC} \leq 5.5\text{V}$                  |                   |     | 250<br>250<br>500 | ns          |
| $t_{PD0}$                | Output Delay to '0'        | AC Test<br>$4.5\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.7\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.5\text{V} \leq V_{CC} \leq 5.5\text{V}$                  |                   |     | 250<br>250<br>500 | ns          |
| $t_{SV}$                 | CS to Status Valid         | AC Test<br>$4.5\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.7\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.5\text{V} \leq V_{CC} \leq 5.5\text{V}$                  |                   |     | 250<br>250<br>500 | ns          |
| $t_{DF}$                 | CS to DO in High Impedance | AC Test<br>$CS = V_{IL}$<br>$4.5\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.7\text{V} \leq V_{CC} \leq 5.5\text{V}$<br>$2.5\text{V} \leq V_{CC} \leq 5.5\text{V}$ |                   |     | 100<br>100<br>200 | ns          |
| $t_{WP}$                 | Write Cycle Time           |  |                   |     | 10                | ms          |
|                          |                            | $4.5\text{V} \leq V_{CC} \leq 5.5\text{V}$   |                   | 3   |                   | ms          |
| Endurance <sup>(1)</sup> | 5.0V, 25°C, Page Mode      |  | 1 M               |     |                   | Write Cycle |

Note: 1. This parameter is characterized and is not 100% tested.

## Instruction Set for the AT93C46C

| Instruction | SB | Op Code | Address                         | Comments   |
|-------------|----|---------|---------------------------------|--|
|             |    |         | x 16                            |  |
| READ        | 1  | 10      | A <sub>5</sub> - A <sub>0</sub> | Reads data stored in memory, at specified address.                         |
| EWEN        | 1  | 00      | 11XXXX                          | Write enable must precede all programming modes.                           |
| ERASE       | 1  | 11      | A <sub>5</sub> - A <sub>0</sub> | Erase memory location A <sub>n</sub> - A <sub>0</sub> .                    |
| WRITE       | 1  | 01      | A <sub>5</sub> - A <sub>0</sub> | Writes memory location A <sub>n</sub> - A <sub>0</sub> .                   |
| ERAL        | 1  | 00      | 10XXXX                          | Erases all memory locations. Valid only at V <sub>CC</sub> = 4.5V to 5.5V. |
| WRAL        | 1  | 00      | 01XXXX                          | Writes all memory locations. Valid only at V <sub>CC</sub> = 4.5V to 5.5V. |
| EWDS        | 1  | 00      | 00XXXX                          | Disables all programming instructions.                                     |

## Functional Description

The AT93C46C is accessed via a simple and versatile three-wire serial communication interface. Device operation is controlled by seven instructions issued by the host processor. **A valid instruction starts with a rising edge of CS** and consists of a Start Bit (logic “1”) followed by the appropriate Op Code and the desired memory Address location.

**READ (READ):** The Read (READ) instruction contains the Address code for the memory location to be read. After the instruction and address are decoded, data from the selected memory location is available at the serial output pin DO. Output data changes are synchronized with the rising edges of serial clock SK. It should be noted that a dummy bit (logic “0”) precedes the 16-bit data output string.

**ERASE/WRITE (EWEN):** To assure data integrity, the part automatically goes into the Erase/Write Disable (EWDS) state when power is first applied. An Erase/Write Enable (EWEN) instruction must be executed first before any programming instructions can be carried out. Please note that once in the Erase/Write Enable state, programming remains enabled until an Erase/Write Disable (EWDS) instruction is executed or V<sub>CC</sub> power is removed from the part.

**ERASE (ERASE):** The Erase (ERASE) instruction programs all bits in the specified memory location to the logical “1” state. The self-timed erase cycle starts once the ERASE instruction and address are decoded. The DO pin outputs the READY/BUSY status of the part if CS is brought high after being kept low for a minimum of 250 ns (t<sub>CS</sub>). A logic “1” at pin DO indicates that the selected memory location has been erased, and the part is ready for another instruction.

**WRITE (WRITE):** The Write (WRITE) instruction contains the 16 bits of data to be written into the specified memory location. The self-timed programming cycle t<sub>WP</sub> starts after the last bit of data is received at serial data input pin DI. The DO pin outputs the READY/BUSY status of the part if CS is brought high after being kept low for a minimum of 250 ns (t<sub>CS</sub>). A logic “0” at DO indicates that programming is still in progress. A logic “1” indicates that the memory location at the specified address has been written with the data pattern contained in the instruction and the part is ready for further instructions. **A Ready/Busy Status cannot be obtained if the CS is brought high after the end of the self-timed programming cycle, t<sub>WP</sub>.**



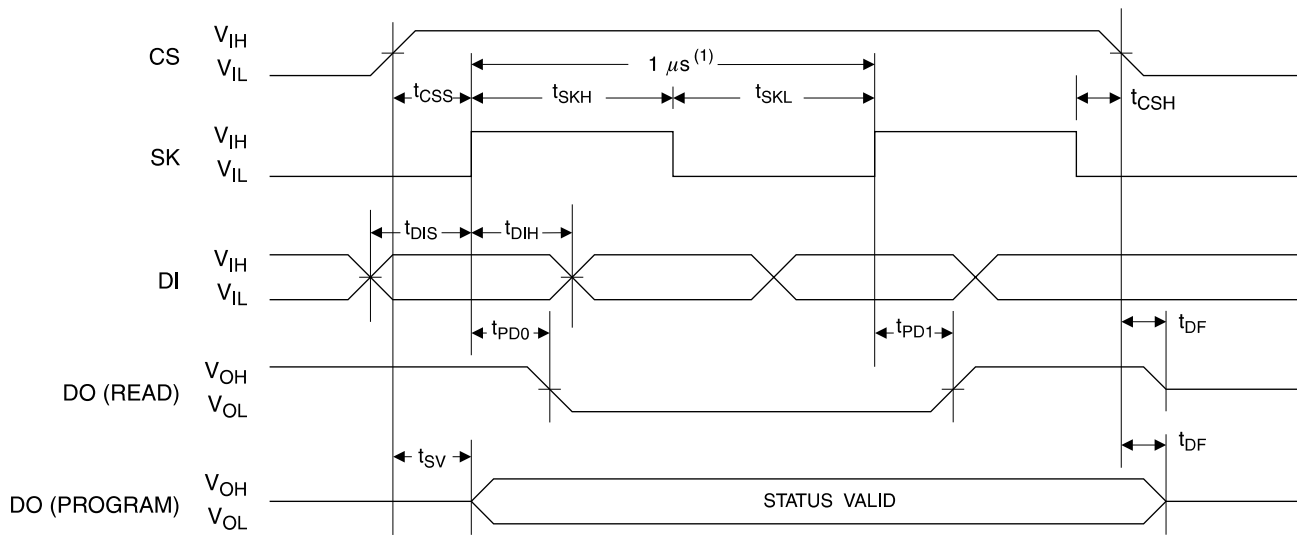
**ERASE ALL (ERAL):** The Erase All (ERAL) instruction programs every bit in the memory array to the logic “1” state and is primarily used for testing purposes. The DO pin outputs the READY/BUSY status of the part if CS is brought high after being kept low for a minimum of 250 ns ( $t_{CS}$ ). The ERAL instruction is valid only at  $V_{CC} = 5.0V \pm 10\%$ .

**WRITE ALL (WRAL):** The Write All (WRAL) instruction programs all memory locations with the data patterns specified in the instruction. The DO pin outputs the READY/BUSY status of the part if CS is brought high after being kept low for a minimum of 250 ns ( $t_{CS}$ ). The WRAL instruction is valid only at  $V_{CC} = 5.0V \pm 10\%$ .

**ERASE/WRITE DISABLE (EWDS):** To protect against accidental data disturb, the Erase/Write Disable (EWDS) instruction disables all programming modes and should be executed after all programming operations. The operation of the READ instruction is independent of both the EWEN and EWDS instructions and can be executed at any time.

## Timing Diagrams

### Synchronous Data Timing

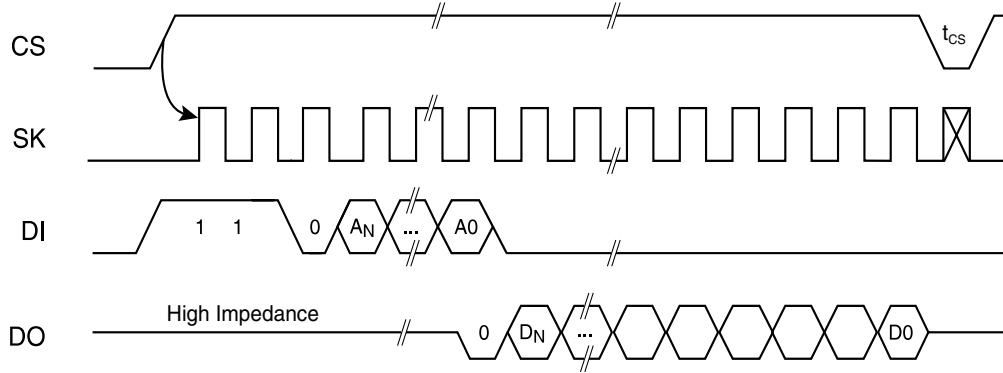


Note: This is the minimum SK period.

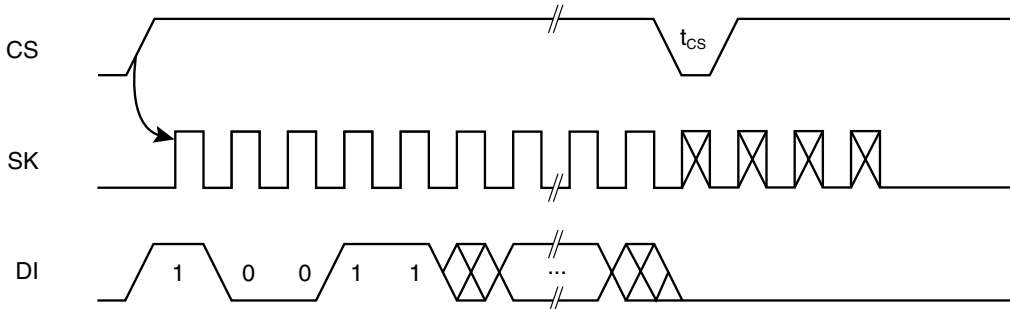
## Organization Key for Timing Diagrams

|            |                 |
|------------|-----------------|
|            | <b>AT93C46C</b> |
| <b>I/O</b> | <b>x 16</b>     |
| $A_N$      | $A_5$           |
| $D_N$      | $D_{15}$        |

### READ Timing

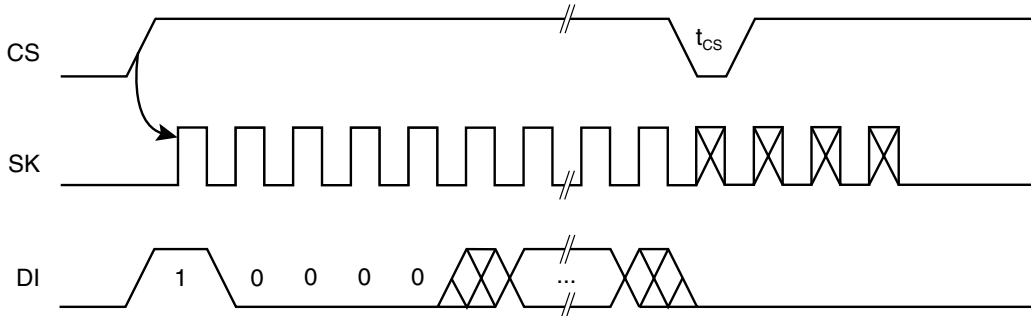


### EWEN Timing<sup>(1)</sup>



Note: 1. Requires a minimum of nine clock cycles.

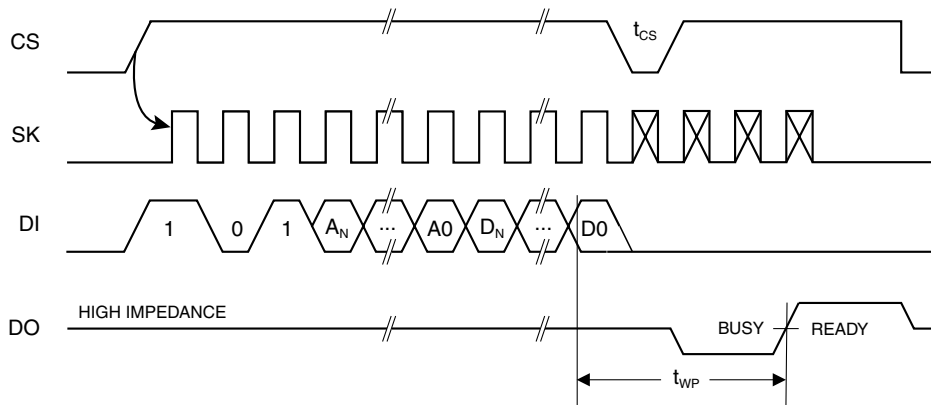
### EWDS Timing<sup>(1)</sup>



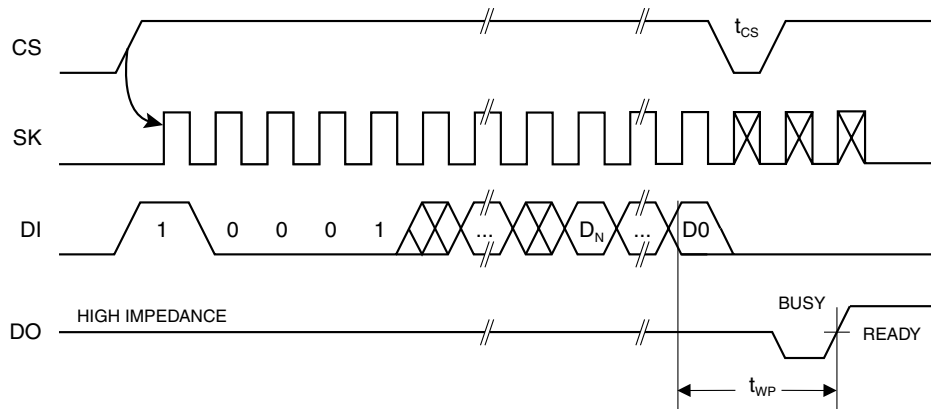
Note: 1. Requires a minimum of nine clock cycles.



**WRITE Timing**

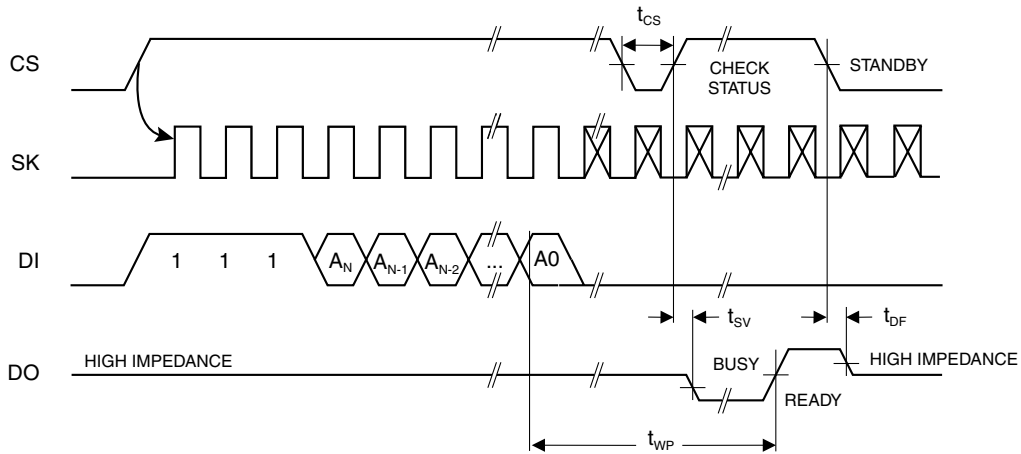


**WRAL Timing<sup>(1)(2)</sup>**

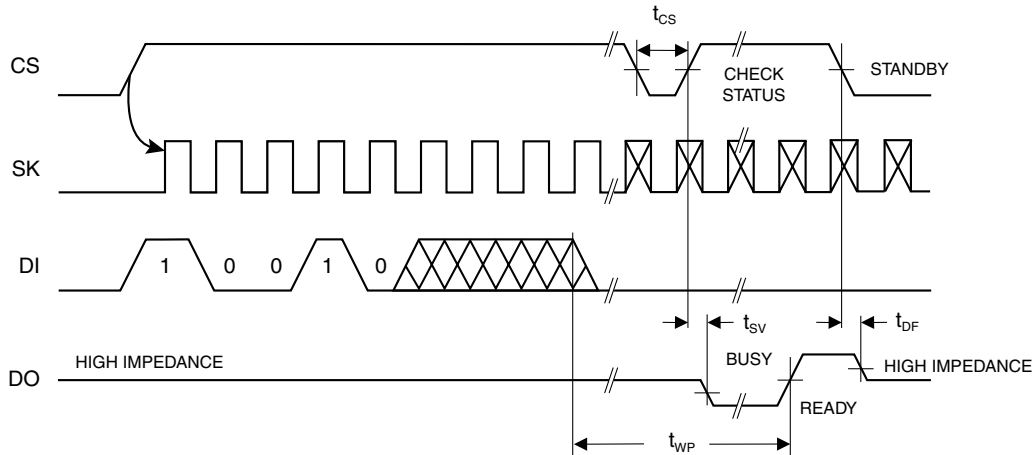


- Notes:
1. Valid only at  $V_{CC} = 4.5V$  to  $5.5V$ .
  2. Requires a minimum of nine clock cycles.

## ERASE Timing



## ERAL Timing<sup>(1)</sup>



Note: 1. Valid only at  $V_{CC} = 4.5V$  to  $5.5V$ .

**Ordering Information**

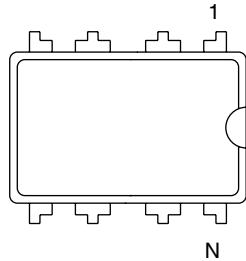
| Ordering Code                          | Package    | Operation Range               |
|--|------------|-------------------------------|
| AT93C46C-10PI-2.7<br>AT93C46C-10SI-2.7 | 8P3<br>8S1 | Industrial<br>(-40°C to 85°C) |
| AT93C46C-10PI-2.5<br>AT93C46C-10SI-2.5 | 8P3<br>8S1 | Industrial<br>(-40°C to 85°C) |

Note: For 2.7V and 2.5V devices used in the 4.5V to 5.5V range, please refer to performance values in the AC and DC characteristics table.

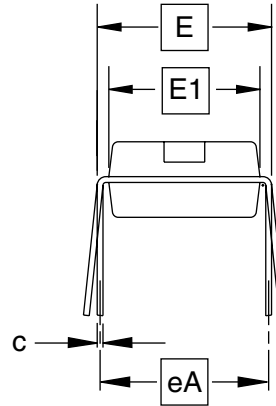
| Package Type |   |
|--------------|---|
| <b>8P3</b>   | 8-lead, 0.300" Wide, Plastic Dual Inline Package (PDIP)           |
| <b>8S1</b>   | 8-lead, 0.150" Wide, Plastic Gull Wing Small Outline (JEDEC SOIC) |
| Options      |   |
| <b>-2.7</b>  | Low Voltage (2.7V to 5.5V)  |
| <b>-2.5</b>  | Low Voltage (2.5V to 5.5V)  |

# Packaging Information

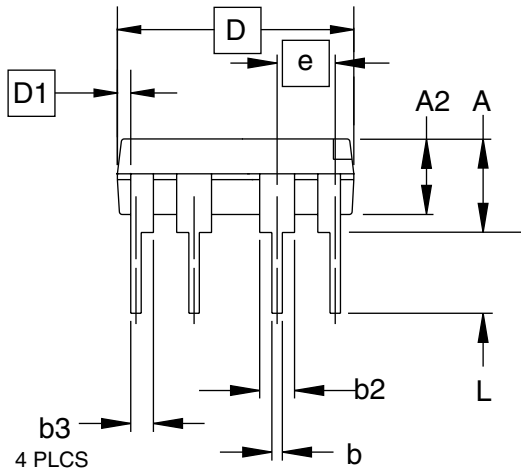
## 8P3 – PDIP



Top View



End View



Side View

**COMMON DIMENSIONS**  
(Unit of Measure = inches)

| SYMBOL | MIN       | NOM   | MAX   | NOTE |
|--------|-----------|-------|-------|------|
| A      |           |       | 0.210 | 2    |
| A2     | 0.115     | 0.130 | 0.195 |      |
| b      | 0.014     | 0.018 | 0.022 | 5    |
| b2     | 0.045     | 0.060 | 0.070 | 6    |
| b3     | 0.030     | 0.039 | 0.045 | 6    |
| c      | 0.008     | 0.010 | 0.014 |      |
| D      | 0.355     | 0.365 | 0.400 | 3    |
| D1     | 0.005     |       |       | 3    |
| E      | 0.300     | 0.310 | 0.325 | 4    |
| E1     | 0.240     | 0.250 | 0.280 | 3    |
| e      | 0.100 BSC |       |       |      |
| eA     | 0.300 BSC |       |       | 4    |
| L      | 0.115     | 0.130 | 0.150 | 2    |

- Notes:
1. This drawing is for general information only; refer to JEDEC Drawing MS-001, Variation BA for additional information.
  2. Dimensions A and L are measured with the package seated in JEDEC seating plane Gauge GS-3.
  3. D, D1 and E1 dimensions do not include mold Flash or protrusions. Mold Flash or protrusions shall not exceed 0.010 inch.
  4. E and eA measured with the leads constrained to be perpendicular to datum.
  5. Pointed or rounded lead tips are preferred to ease insertion.
  6. b2 and b3 maximum dimensions do not include Dambar protrusions. Dambar protrusions shall not exceed 0.010 (0.25 mm).

01/09/02



2325 Orchard Parkway  
San Jose, CA 95131

**TITLE**

**8P3**, 8-lead, 0.300" Wide Body, Plastic Dual  
In-line Package (PDIP)

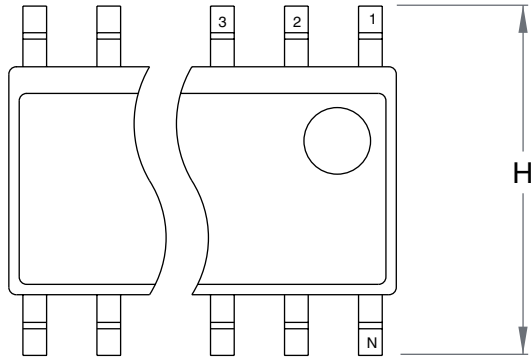
**DRAWING NO.**

8P3

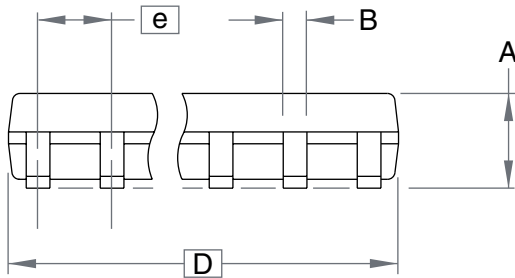
**REV.**

B

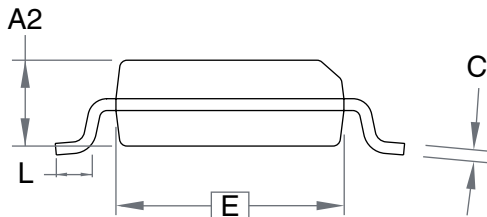
8S1 – JEDEC SOIC



Top View



Side View



End View

COMMON DIMENSIONS  
(Unit of Measure = mm)

| SYMBOL | MIN      | NOM | MAX  | NOTE |
|--------|----------|-----|------|------|
| A      | -        | -   | 1.75 |      |
| B      | -        | -   | 0.51 |      |
| C      | -        | -   | 0.25 |      |
| D      | -        | -   | 5.00 |      |
| E      | -        | -   | 4.00 |      |
| e      | 1.27 BSC |     |      |      |
| H      | -        | -   | 6.20 |      |
| L      | -        | -   | 1.27 |      |

Note: This drawing is for general information only. Refer to JEDEC Drawing MS-012 for proper dimensions, tolerances, datums, etc.

10/10/01



2325 Orchard Parkway  
San Jose, CA 95131

**TITLE**  
8S1, 8-lead (0.150" Wide Body), Plastic Gull Wing  
Small Outline (JEDEC SOIC)

**DRAWING NO.**  
8S1

**REV.**  
A





## Atmel Headquarters

### *Corporate Headquarters*

2325 Orchard Parkway  
San Jose, CA 95131  
TEL 1(408) 441-0311  
FAX 1(408) 487-2600

### *Europe*

Atmel Sarl  
Route des Arsenaux 41  
Case Postale 80  
CH-1705 Fribourg  
Switzerland  
TEL (41) 26-426-5555  
FAX (41) 26-426-5500

### *Asia*

Room 1219  
Chinachem Golden Plaza  
77 Mody Road Tsimshatsui  
East Kowloon  
Hong Kong  
TEL (852) 2721-9778  
FAX (852) 2722-1369

### *Japan*

9F, Tonetsu Shinkawa Bldg.  
1-24-8 Shinkawa  
Chuo-ku, Tokyo 104-0033  
Japan  
TEL (81) 3-3523-3551  
FAX (81) 3-3523-7581

## Atmel Operations

### *Memory*

2325 Orchard Parkway  
San Jose, CA 95131  
TEL 1(408) 441-0311  
FAX 1(408) 436-4314

### *Microcontrollers*

2325 Orchard Parkway  
San Jose, CA 95131  
TEL 1(408) 441-0311  
FAX 1(408) 436-4314

La Chantrerie  
BP 70602  
44306 Nantes Cedex 3, France  
TEL (33) 2-40-18-18-18  
FAX (33) 2-40-18-19-60

### *ASIC/ASSP/Smart Cards*

Zone Industrielle  
13106 Rousset Cedex, France  
TEL (33) 4-42-53-60-00  
FAX (33) 4-42-53-60-01

1150 East Cheyenne Mtn. Blvd.  
Colorado Springs, CO 80906  
TEL 1(719) 576-3300  
FAX 1(719) 540-1759

Scottish Enterprise Technology Park  
Maxwell Building  
East Kilbride G75 0QR, Scotland  
TEL (44) 1355-803-000  
FAX (44) 1355-242-743

### *RF/Automotive*

Theresienstrasse 2  
Postfach 3535  
74025 Heilbronn, Germany  
TEL (49) 71-31-67-0  
FAX (49) 71-31-67-2340

1150 East Cheyenne Mtn. Blvd.  
Colorado Springs, CO 80906  
TEL 1(719) 576-3300  
FAX 1(719) 540-1759

### *Biometrics/Imaging/Hi-Rel MPU/ High Speed Converters/RF Datacom*

Avenue de Rochepleine  
BP 123  
38521 Saint-Egreve Cedex, France  
TEL (33) 4-76-58-30-00  
FAX (33) 4-76-58-34-80

---

### *e-mail*

[literature@atmel.com](mailto:literature@atmel.com)

### *Web Site*

<http://www.atmel.com>

### © Atmel Corporation 2002.

Atmel Corporation makes no warranty for the use of its products, other than those expressly contained in the Company's standard warranty which is detailed in Atmel's Terms and Conditions located on the Company's web site. The Company assumes no responsibility for any errors which may appear in this document, reserves the right to change devices or specifications detailed herein at any time without notice, and does not make any commitment to update the information contained herein. No licenses to patents or other intellectual property of Atmel are granted by the Company in connection with the sale of Atmel products, expressly or by implication. Atmel's products are not authorized for use as critical components in life support devices or systems.

ATMEL® is the registered trademark of Atmel.

Other terms and product names may be the trademarks of others.



Printed on recycled paper.